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	Application Number	10/759,079-Conf. #7174	

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 1

Complete if Known					
Application Number	10/759,079-Conf. #7174				
Filing Date	January 20, 2004				
First Named Inventor	Kie Y. Ahn				
Art Unit	2818				
Examiner Name	D. Nhu				
Attorney Docket Number	M4065.0383/P383-C				

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
W.	**AA	6,259,407	07/10/2001	Tran	Ų	

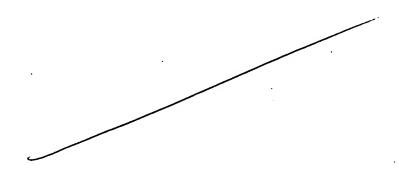
FOREIGN PATENT DOCUMENTS							
Examiner	Cite	Foreign Patent Document	Publication	Name of Patentee or	Pages, Columns, Lines,		
Initials*	No.1	Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Date MM-DD-YYYY	Applicant of Cited Document	Where Relevant Passages or Relevant Figures Appear	₹°	

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INFORMATION DISCLOSURE		Filing Date	January 20, 2004	1' '		
		First Named Inventor	Kie Y. Ahn			
O A CONTROL OF A C		Art Unit	N/A			
(Use as	many she	ets &	s necessary)	Examiner Name	Not Yet Assigned]
1		of	1	Attorney Docket Number	M4065.0383/P383-C]
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Examiner	Cita	Document Number	Publication Date	Name of Patentee or	Pages, Columns, Lines, Where Relevant Passages or Relevant
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Examiner Initials*	Cite No.1	Foreign Patent Document Country Code ³ -Humber ³ -Hind Code ⁶ (# known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Τ°	
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Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the Item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Te
Pr	CA	"Silicon Micromachined Waveguides for Millimeter-Wave and Submillimeter-Wave Frequencies" by William R. McGarth, Christopher Walker, Markus Yap, and Yu-Chong Tai, IEE Microwave and Guided Wave Letters, Vol. 3, No. 3, March 1993, Pages 61-63.*	
T	СВ	"Si and SiGe Millimeter-Wave Integrated Circuits" by Peter Russer, IEE Transactions on Microwave Theory and Techniques, Vol. 46, No. 5, May 1998, Pages 590-603"	
T	СС	Spigel et al., "Impact of Light Illumination and Passivation Layer on Silicon Finite Ground Coplanar Waveguide Transmission Une Properties", October 2000, IEE Transaction on Microwave Theory and Techniques, Volume 48, No. 10, pages 1673-1679.*	
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Examiner	37.10	Date	10/14/04
Signature	Now all	Considered	<u> </u>